



Atty. Docket No.: SENS.005US0
Application No.: 10/056,906

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

#121TOS
Anpon
10/23/03

Applicant(s): Wayne G. Renken

Title: Process Condition Sensing Wafer and Data Analysis System

Application No.: 10/056,906

Filing Date: January 24, 2002

Examiner: Charles D. Garber

Group Art Unit: 2856

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Mail Stop Fee Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

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**INFORMATION DISCLOSURE STATEMENT
UNDER 37 CFR § 1.97(c) WITH FEE**

Dear Sir:

Pursuant to 37 C.F.R. § 1.56, § 1.97 and § 1.98, Applicant(s) wish to call the following document (copy enclosed) to the attention of the Examiner for the above-identified patent application.

A form PTO-1449 listing this document is enclosed.

Citation of the above documents shall not be construed as:

1. an admission that the documents are necessarily prior art with respect to the instant invention;
2. a representation that a search has been made, a representation that a search has been made, (other than as indicated by any cited document); or
3. an admission that the information cited herein is, or is considered to be, material to patentability as defined in § 1.56(b).

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A check for \$180.00 for the Information Disclosure Statement fee under 37 C.F.R. § 1.17(p), is enclosed as set forth in the accompanying transmittal letter. The Commissioner is hereby authorized to charge any additional fees which may be required, or credit any overpayment to Deposit Account No. 502664. This paper is being submitted in duplicate.

Respectfully submitted,


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October 14, 2003

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